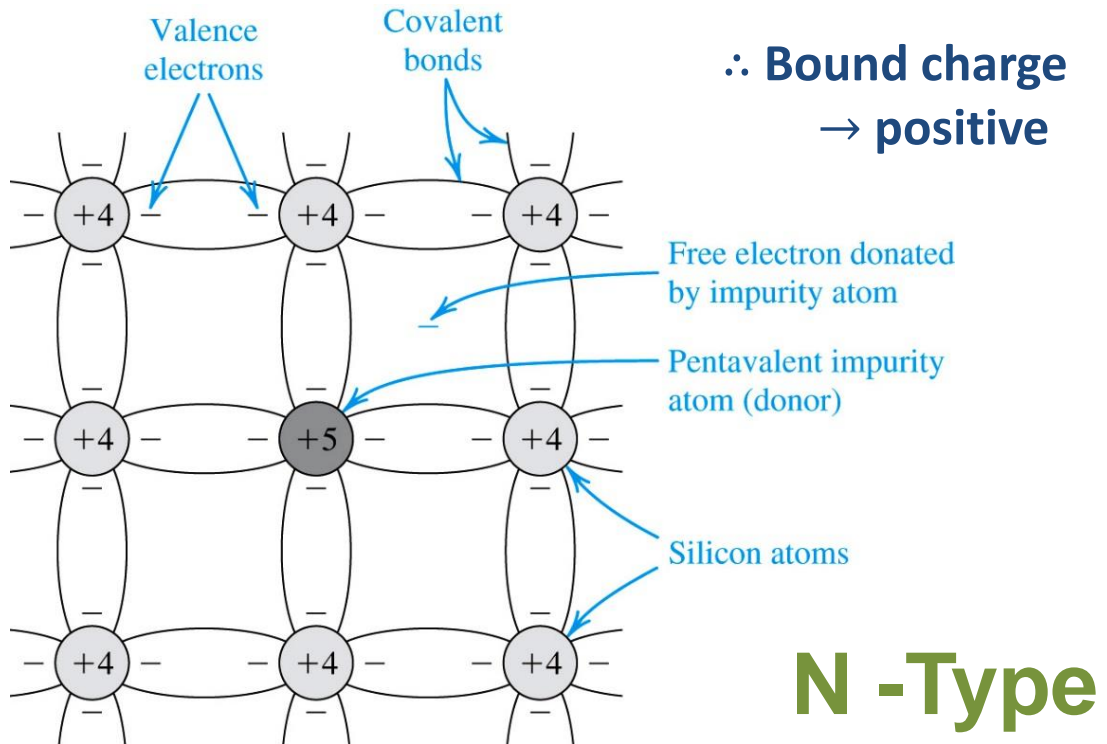


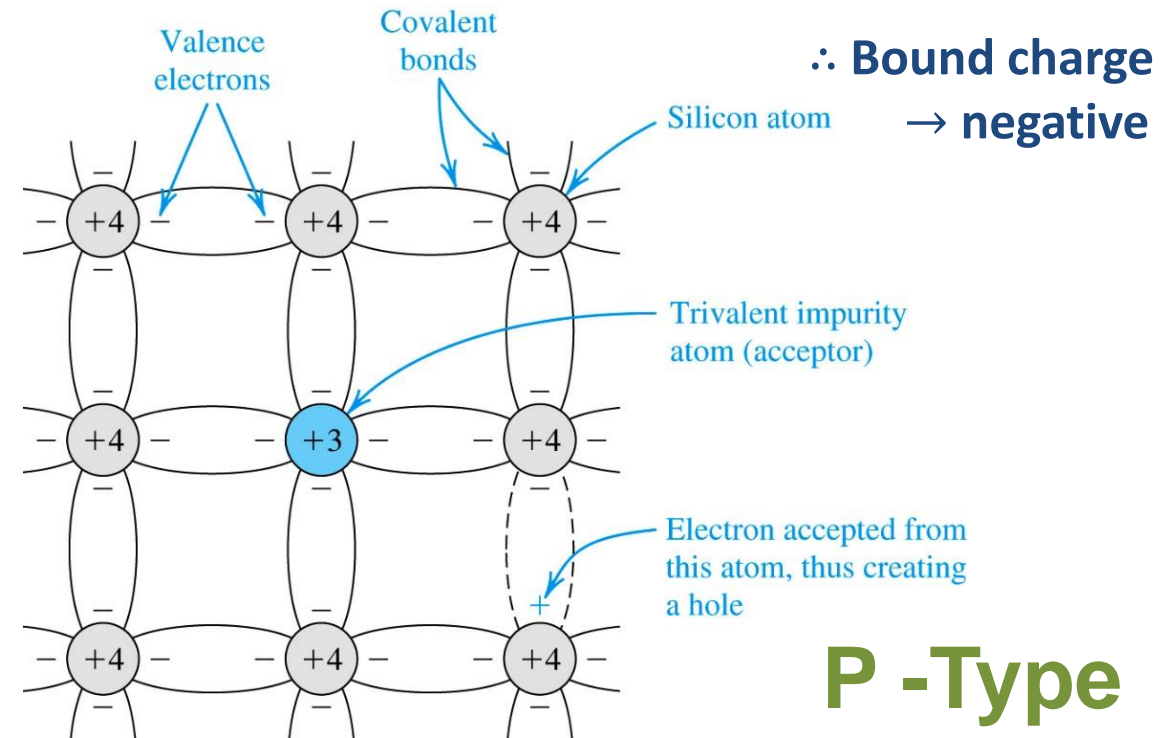
Last Lecture → Semiconductor Types

8/19/2019

- **Antimony (Sb) – 5 Valence Electrons**
- **n-type: electrons >> holes**
 - Majority carriers – electrons
 - Minority carriers - holes



- **Boron (B) – 3 Valence Electrons**
- **p-type: holes >> electrons**
 - Majority carriers – holes
 - Minority carriers - electrons



Last Lecture → Current Flow in Semiconductors

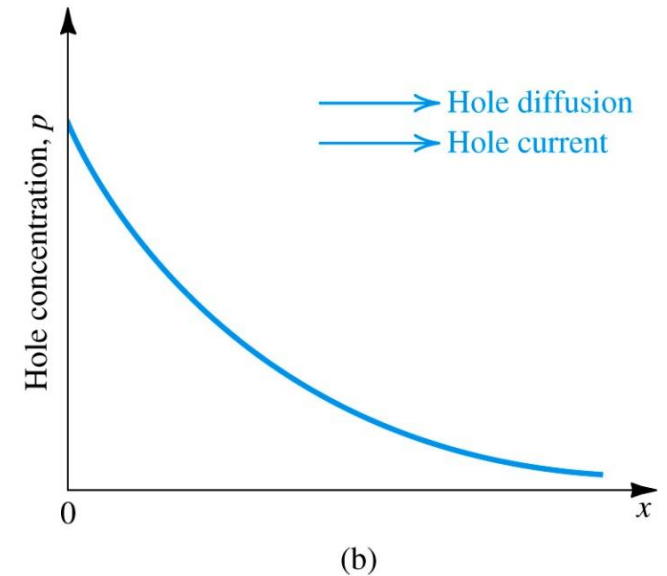
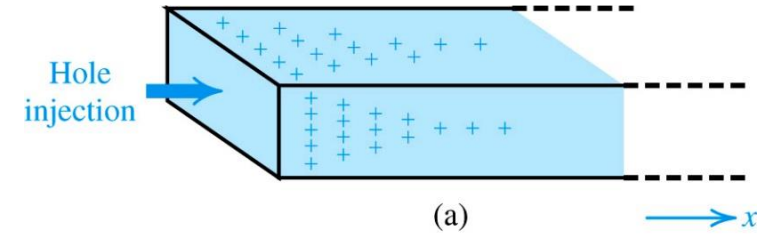
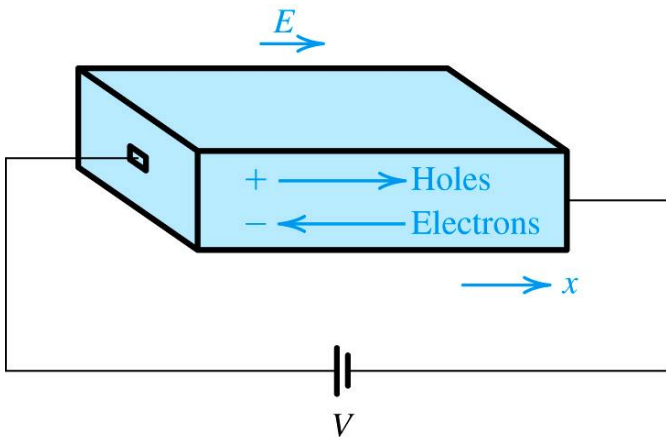
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... there are two distinctly different mechanisms for the movement of charge carriers and hence for current flow in semiconductors: *drift* and *diffusion*

Drift Current

When an electrical field E is established in a semiconductor crystal...

- Holes are accelerated in the direction of E !
- Free electrons are accelerated in the direction opposite of E !



Diffusion Current

When the density of charge carrier in a piece of semiconductor is not uniform...

- Charge carriers will diffuse from the region of high concentration to the region of low concentration!

Problem 3.6

8/19/2019

A young designer, aiming to develop intuition concerning conducting paths within an integrated circuit, examines the end-to-end resistance of a connecting bar 10 μm long, 3 μm wide, and 1 μm thick, made of various materials. The designer considers:

- intrinsic silicon
- n-doped silicon with $N_D=10^{16}/\text{cm}^3$
- n-doped silicon with $N_D=10^{18}/\text{cm}^3$
- p-doped silicon with $N_A=10^{16}/\text{cm}^3$
- Aluminum with resistivity of 2.8 $\mu\Omega\cdot\text{cm}$.

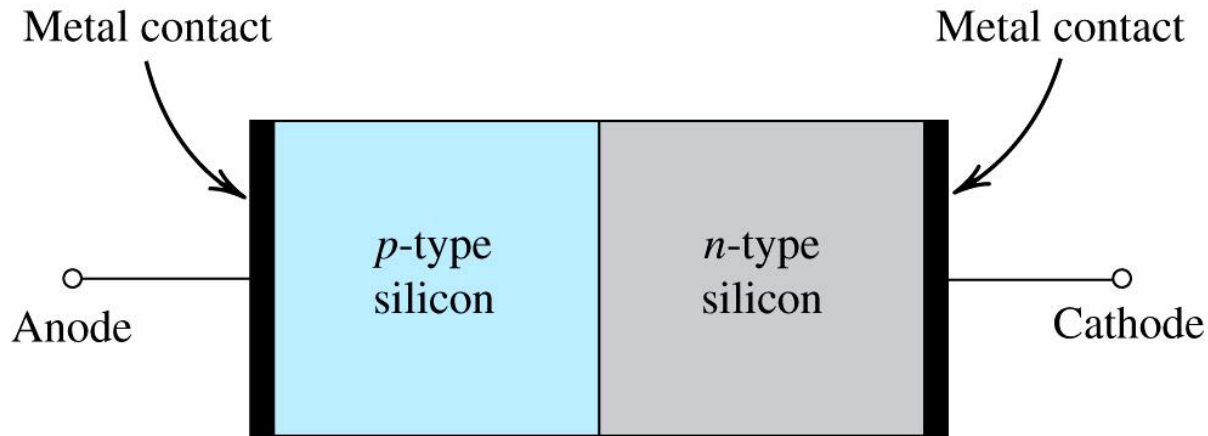
Find the resistance in each case. For intrinsic silicon use the data in Table 3.1. For doped silicon, assume $\mu_n=2.5\cdot\mu_p=1200\text{cm}^2/\text{V}\cdot\text{s}$. (Recall that $R=\rho L/A$)

- Silicon $n_i = 1.5 \times 10^{10} / \text{cm}^3$
- $q = 1.6 \times 10^{-19} \text{ C}$

	n (1/cm ³)	p (1/cm ³)	ρ $\Omega\cdot\text{cm}$	R Ω
a)	1.5×10^{10}	1.5×10^{10}	227×10^3	7.57M
b)	10^{16}	2.25×10^4	0.463	15
c)	10^{18}	2.25×10^2	4.63m	0.15
d)	2.25×10^4	10^{16}	0.768	25.6
e)	-	-	2.8 μ	93.3 μ

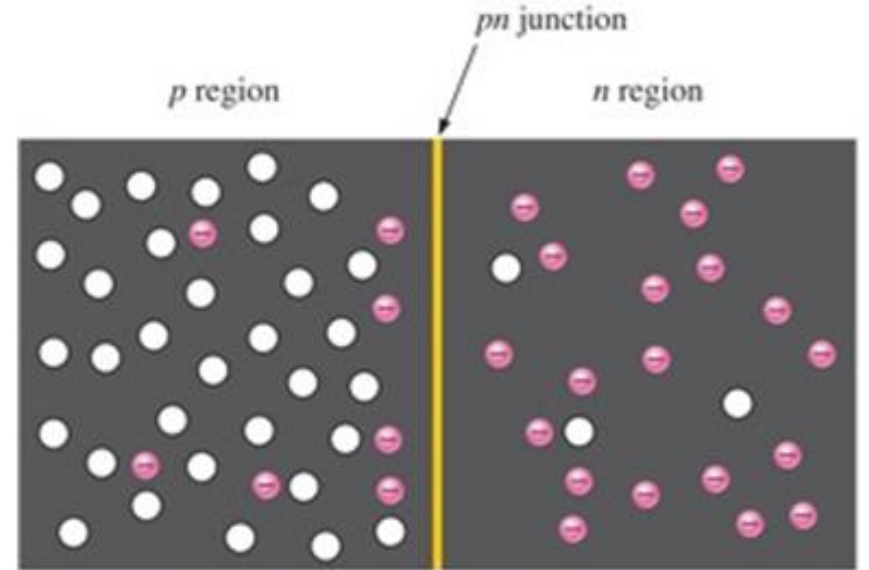
The PN Junction

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- *p*-type semiconductor
- *n*-type semiconductor
- metal contact for connection

Symbol



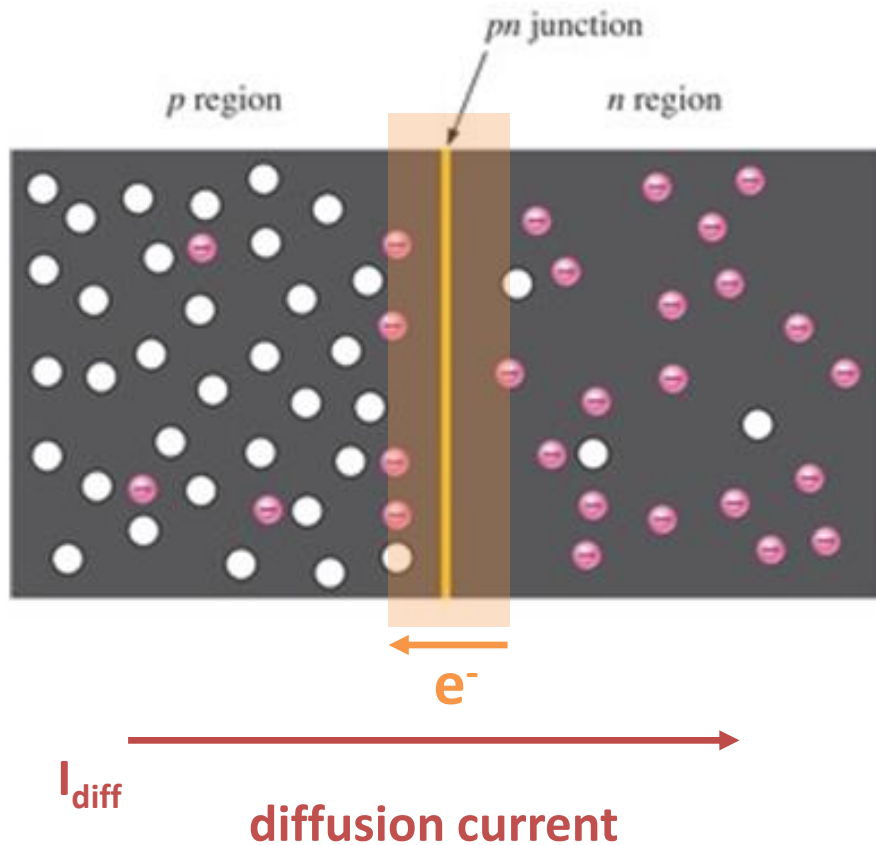
higher holes
concentration

higher e^-
concentration

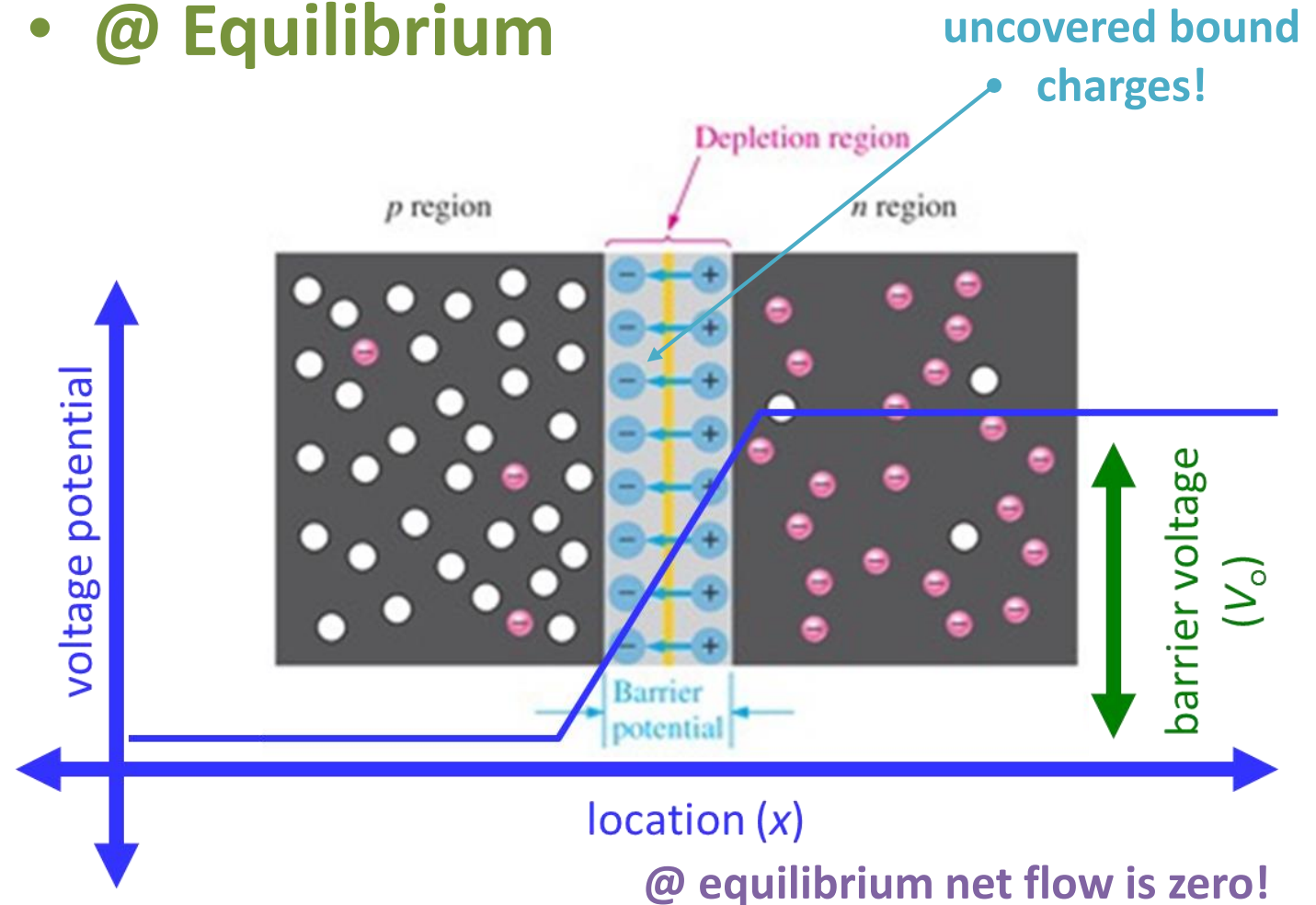
The PN Junction

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- Initially

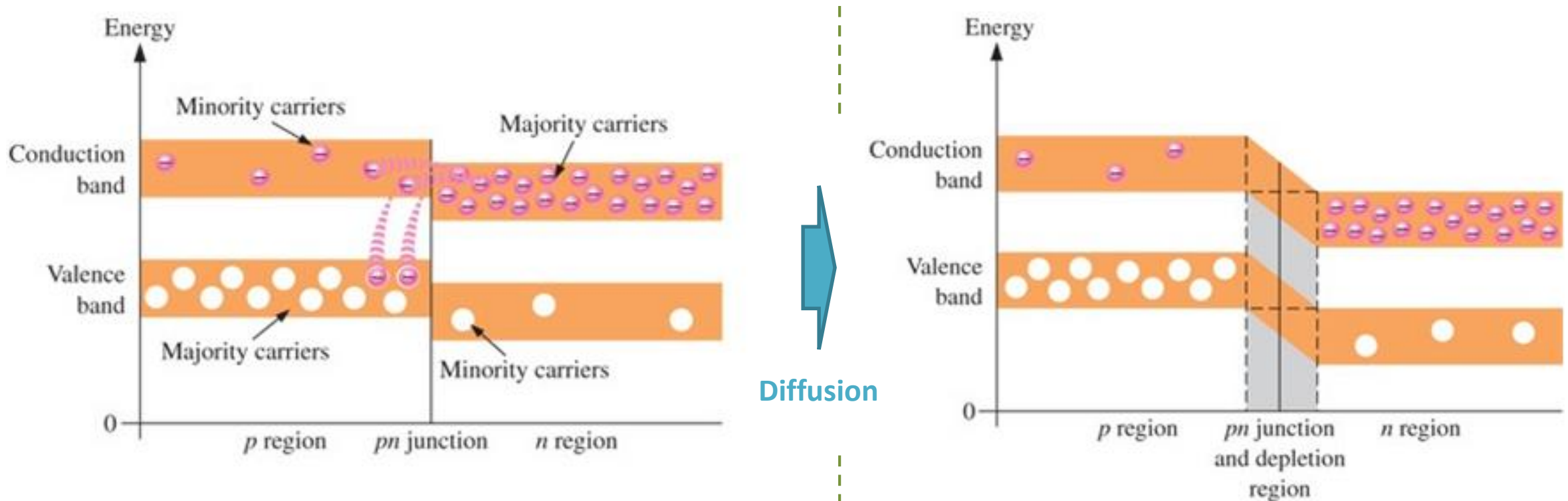


- @ Equilibrium



The Equilibrium PN Junction

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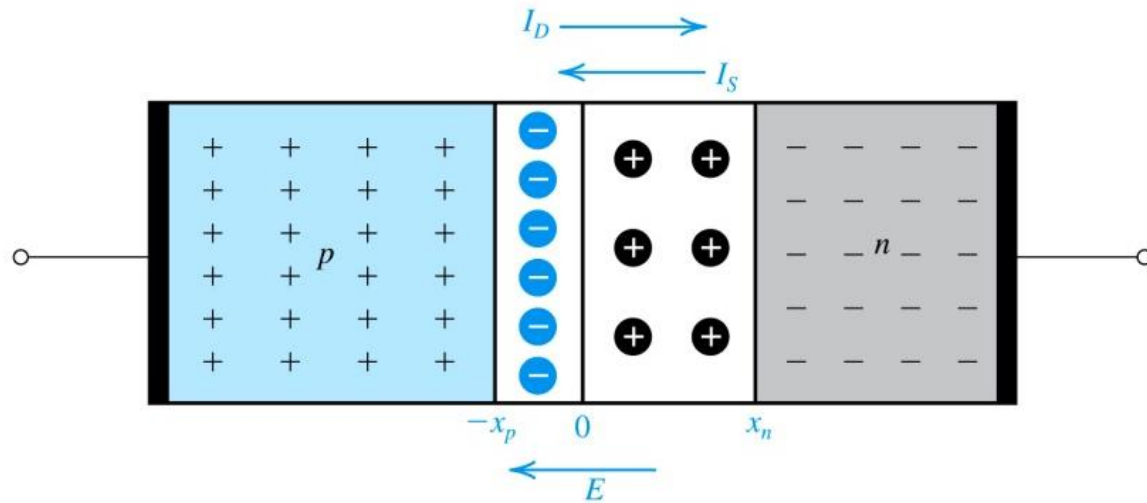


- Energy levels are aligned.
- Free electrons can easily diffuse across the junction.

- The energy level of the n region decreases.
- The depletion region acts like an “energy hill”.

The Equilibrium PN Junction $\rightarrow N_A > N_D$

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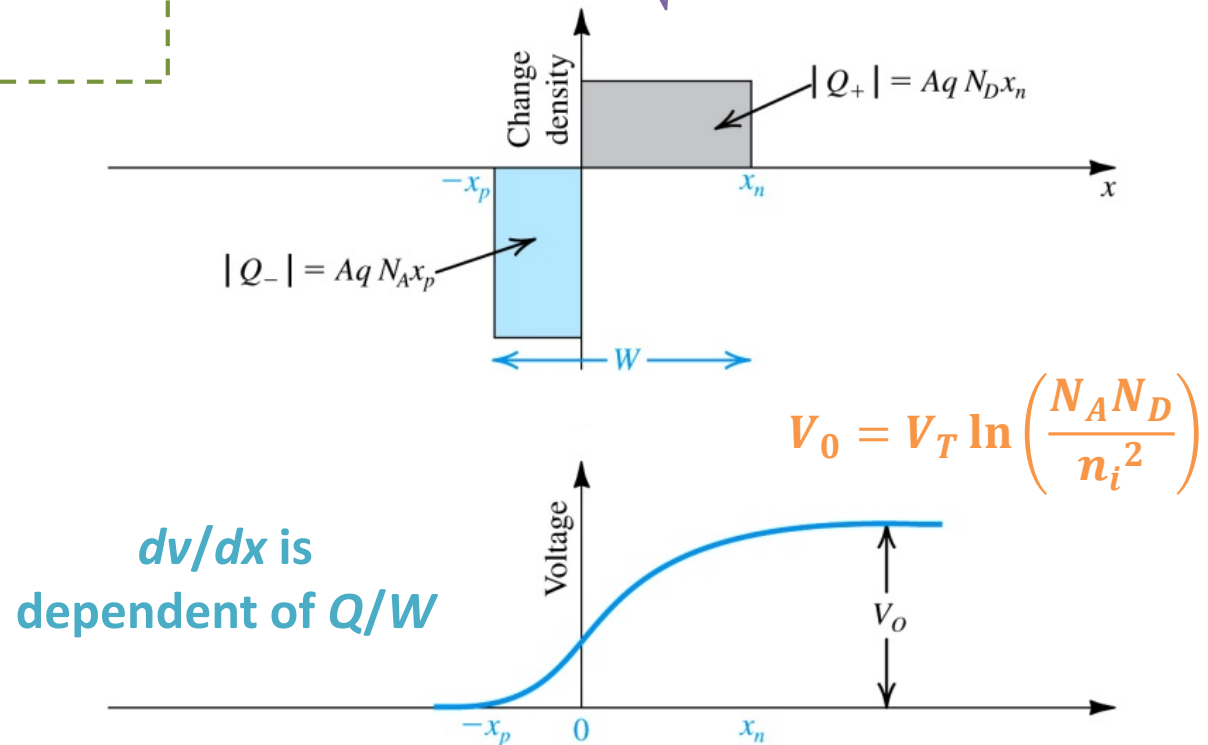
- The depletion region will extend further in to region with “less” doping.
- However, the “number” of uncovered charges is the same.

\therefore charge is equal, but width is different

$$\frac{x_n}{x_p} = \frac{N_A}{N_D}$$

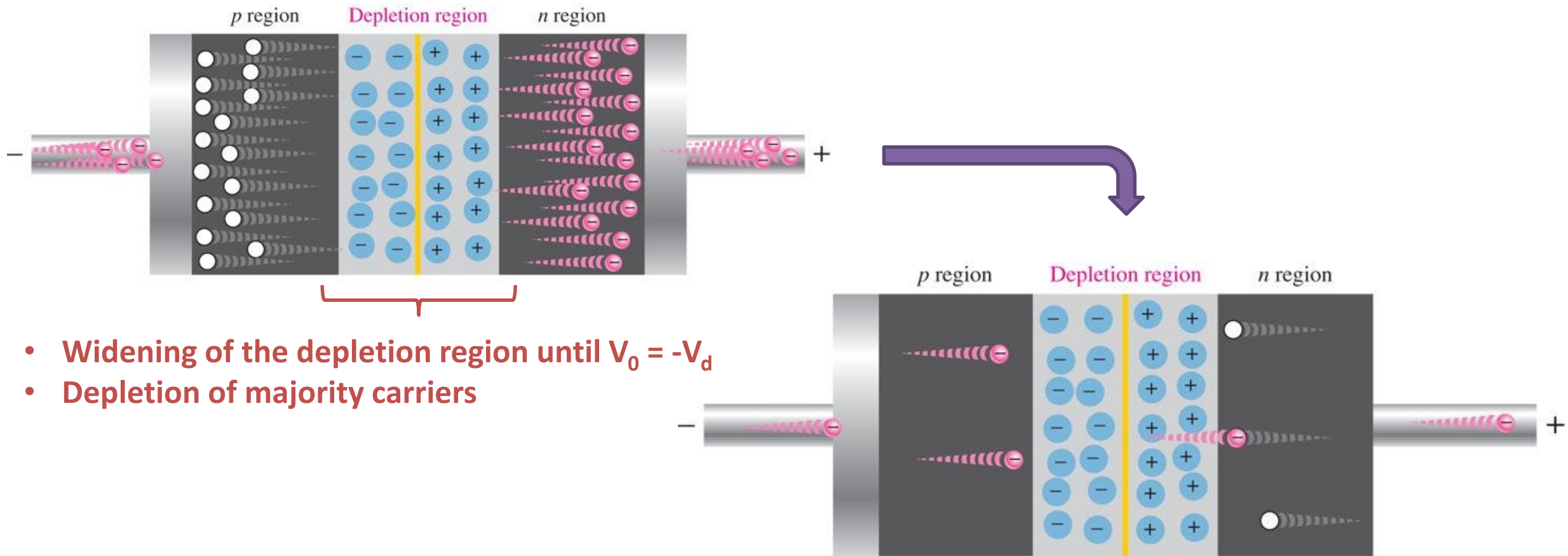
$$W = x_n + x_p$$

$$= \sqrt{\frac{2\epsilon_s}{q} \left[\frac{1}{N_A} + \frac{1}{N_D} \right] [V_0 + V_R]}$$



Reverse-Biased PN Junction $\rightarrow V_d < 0$

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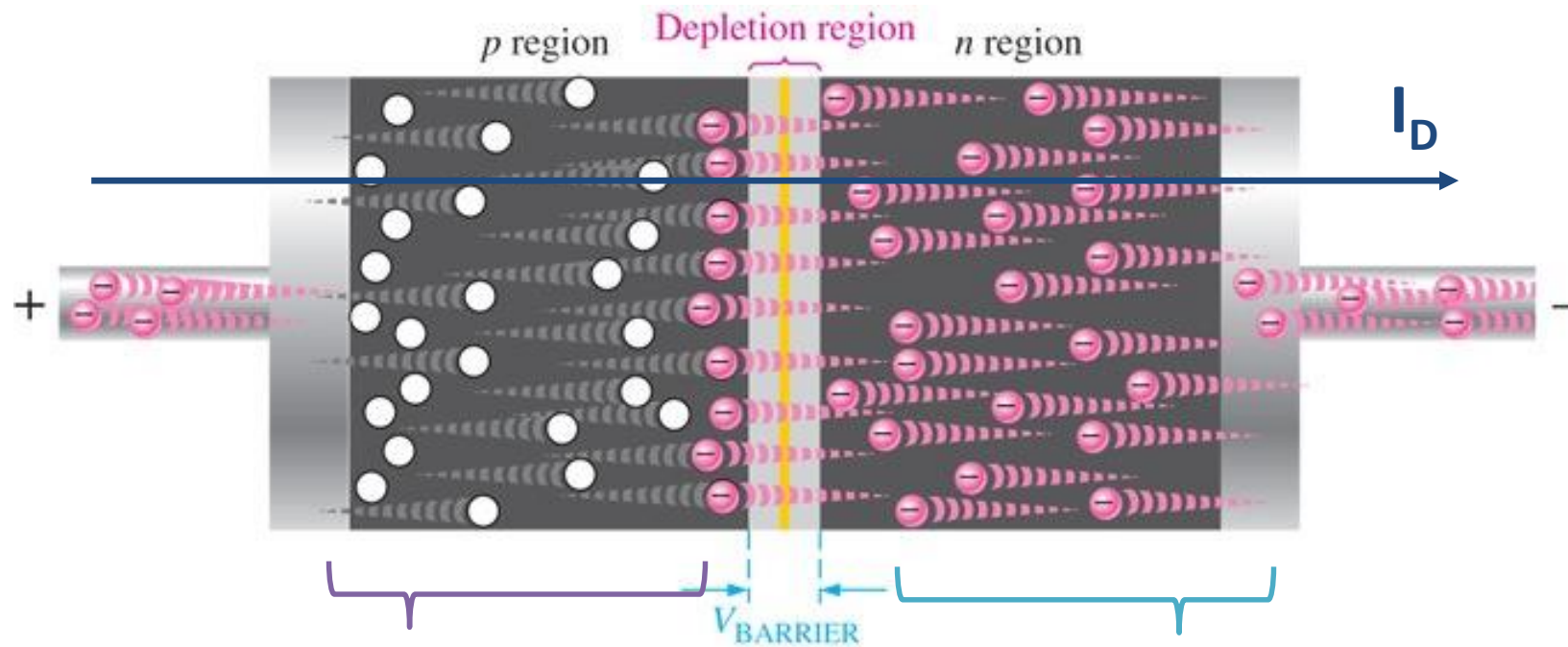


- Widening of the depletion region until $V_0 = -V_d$
- Depletion of majority carriers

- The transition current essentially ceases
- A extremely small current exists do minority carries produced thermally

Forward-Biased PN Junction $\rightarrow V_d > |V_0|$

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Once on p region they become minority carries

Barrier is reduced

Free electrons have enough energy to diffuse across the barrier

Hole current will move the minority carries towards the positive terminal

\rightarrow Thus a steady state current will be established!

Qualitative PN Junction Operation

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Reverse biased case ($\uparrow V_R$)

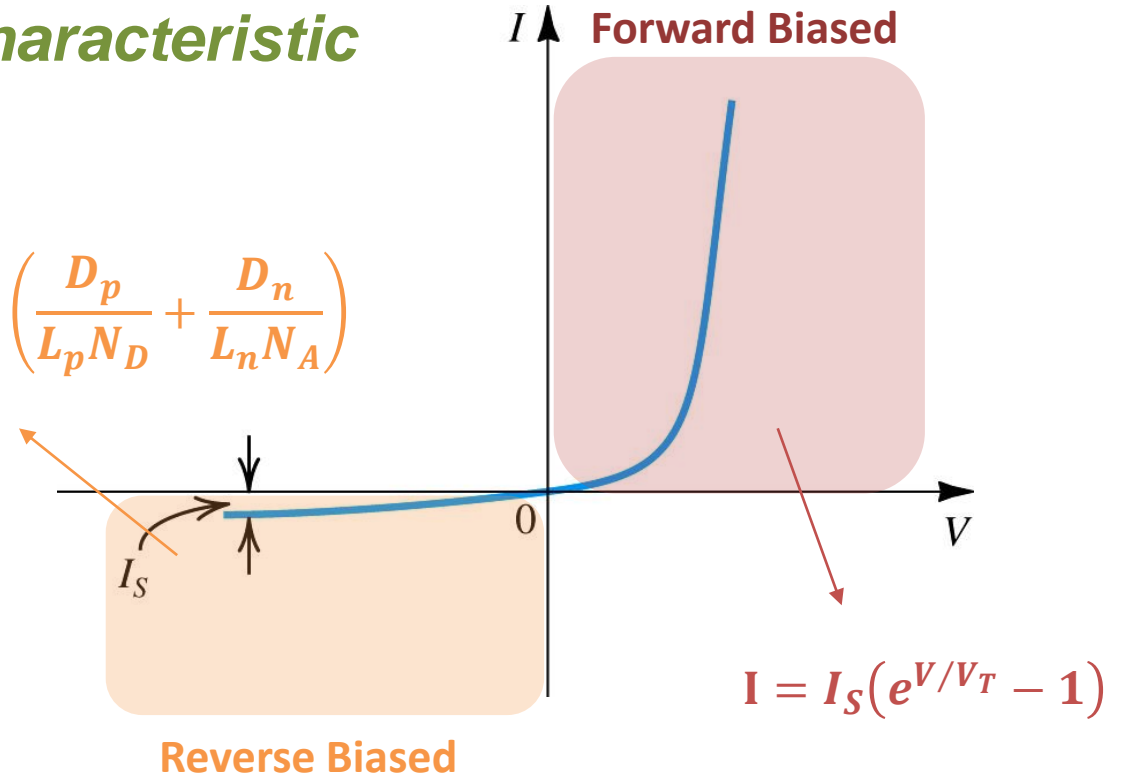
- barrier voltage increases ($\uparrow V_0$)
 - Diffusion decreases... $\therefore \downarrow I_D$
 - @ $V_R > 1V$, $I_D \approx 0A$
- the drift current I_S is unaffected
- $I_{pn} \approx I_S$ (small non-zero current)

Forward biased case ($\uparrow V_F$)

- barrier voltage decreases ($\downarrow V_0$)
 - Diffusion increases ... $\therefore \uparrow I_D$
- the drift current I_S is unaffected
- $I_{pn} \approx I_D - I_S$ (a significant current)

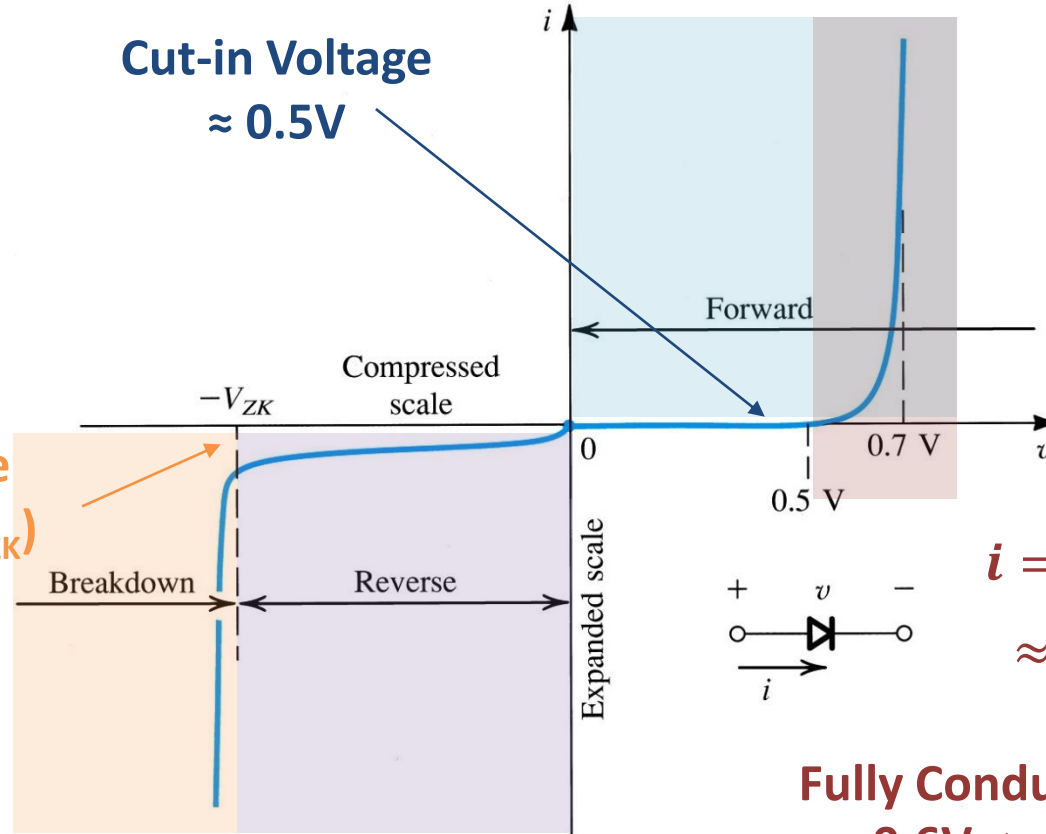
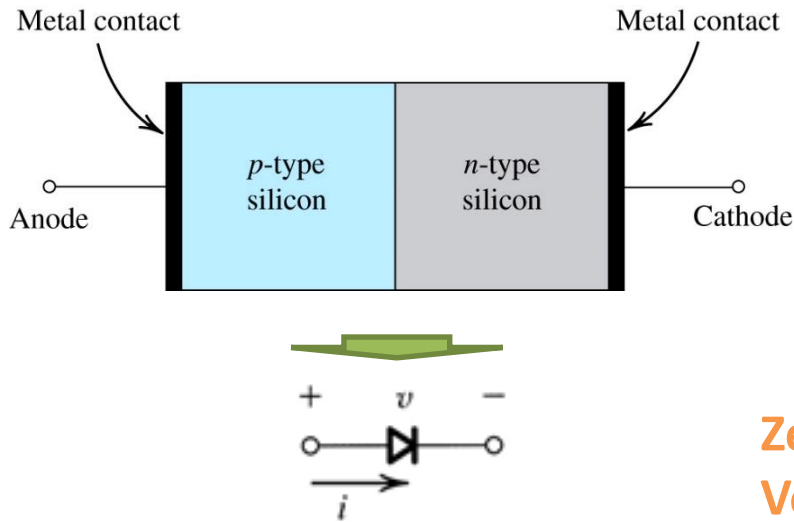
I-V Characteristic

$$I_S = Aqn_i^2 \left(\frac{D_p}{L_p N_D} + \frac{D_n}{L_n N_A} \right)$$



Terminal Characteristics of Diodes

8/19/2019



Characteristic Regions

- **Forward Bias:** $v > 0$
- **On** $v \geq 0.5V$
- **Reverse Bias:** $v < 0$
- **Breakdown:** $v \ll 0$

$$i = I_S(e^{v/V_T} - 1)$$

$$\approx I_S e^{v/V_T}$$

Fully Conducting Region
 $0.6V < v < 0.8V$

- $I_S \rightarrow$ saturation current
- $V_T \rightarrow$ thermal voltage

$$i = -I_S e^{-|v|/V_T}$$

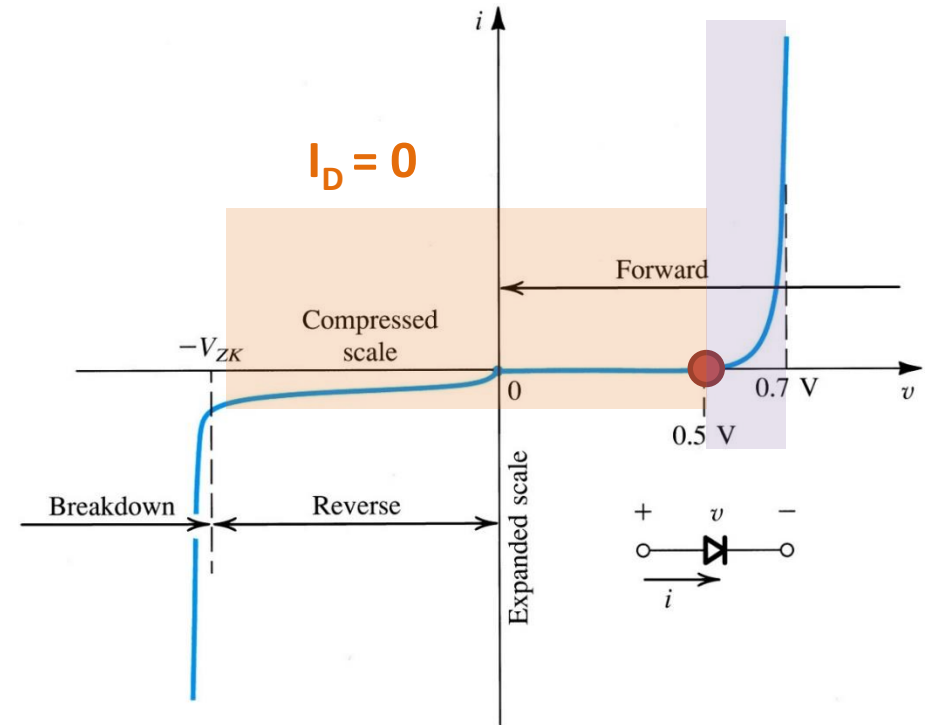
$$i \approx -I_S$$

Diode Models

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- DC Analysis
 - Ideal Model
 - Constant-Voltage-Drop Model
 - Exponential Model
 - Graphical Analysis
 - Numerical Analysis
- AC Analysis
 - Small Signal Model

Your simulation results are as good as your model!!!!



Exponential Model

for $v < 0.5$ $\rightarrow I_D \approx 0$

for $v \geq 0.5$ $\rightarrow I_D \approx I_S e^{v_D/V_T}$

Problem 4.23

8/19/2019

The circuit provided below utilizes three identical diodes having $I_s = 10^{-16}\text{A}$. Find the value of the current I required to obtain an output voltage $V_0 = 2.4\text{V}$. If a current of 1mA is drawn away from the output terminal by a load, what is the change in the output voltage.

